

<b>Notice of References Cited</b>	Application/Control No. 10/046,819	Applicant(s)/Patent Under Reexamination KOBAYASHI ET AL.	
	Examiner David G. Cervetti	Art Unit 2136	Page 1 of 4

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,889,212	05-2005	Wang et al.	705/59
	B	US-5,892,904	04-1999	Atkinson et al.	713/201
	C	US-6,424,718	07-2002	Holloway, Christopher James	380/277
	D	US-6,874,084	03-2005	Dobner et al.	713/156
	E	US-5,870,544	02-1999	Curtis, Bryce Allen	713/201
	F	US-6,694,433	02-2004	Kolouch, James L.	713/176
	G	US-6,292,790	09-2001	Krahn et al.	705/50
	H	US-6,219,787	04-2001	Brewer, Jason M.	713/167
	I	US-6,708,276	03-2004	Yarsa et al.	713/201
	J	US-6,023,764	02-2000	Curtis, Bryce Allen	713/200
	K	US-6,301,661	10-2001	Shambroom, W. David	713/168
	L	US-4,864,616	09-1989	Pond et al.	713/165
	M	US-6,816,596	11-2004	Peinado et al.	380/277

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

<b>Notice of References Cited</b>	Application/Control No. 10/046,819	Applicant(s)/Patent Under Reexamination KOBAYASHI ET AL.	
	Examiner David G. Cervetti	Art Unit 2136	Page 2 of 4

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,260,168	07-2001	Godoroja, Andrei	714/752
	B	US-5,987,523	11-1999	Hind et al.	709/245
	C	US-6,029,000	02-2000	Woolsey et al.	717/147
	D	US-5,369,702	11-1994	Shanton, M. Greg	713/166
	E	US-6,397,330	05-2002	Elgamal et al.	713/164
	F	US-6,839,849	01-2005	Ugon et al.	726/20
	G	US-4,544,833	10-1985	Ugon, Michel	235/379
	H	US-5,479,509	12-1995	Ugon, Michel	713/176
	I	US-6,745,327	06-2004	Messing, John H.	713/170
	J	US-6,108,788	08-2000	Moses et al.	713/155
	K	US-6,901,551	05-2005	Corrigan, III, Brian E.	714/763
	L	US-6,892,230	05-2005	Gu et al.	709/220
	M	US-6,839,844	01-2005	Okano, Hirokazu	713/176

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

<b>Notice of References Cited</b>	Application/Control No. 10/046,819	Applicant(s)/Patent Under Reexamination KOBAYASHI ET AL.	
	Examiner David G. Cervetti	Art Unit 2136	Page 3 of 4

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2002/0083192	06-2002	Alisuag, Cora	709/237
	B	US-2002/0091925	07-2002	Suzuki et al.	713/168
	C	US-5,442,645	08-1995	Ugon et al.	714/736
	D	US-5,642,419	06-1997	Rosen, Sholom S.	705/76
	E	US-5,905,492	05-1999	Straub et al.	715/744
	F	US-5,926,624	07-1999	Katz et al.	709/217
	G	US-5,974,454	10-1999	Apfel et al.	709/221
	H	US-6,091,411	07-2000	Straub et al.	715/747
	I	US-6,163,817	12-2000	Shteyn et al.	710/8
	J	US-6,199,204	03-2001	Donohue, Seamus	717/178
	K	US-6,272,611	08-2001	Wu, Yu-Te	711/173
	L	US-6,275,588	08-2001	Videcrantz et al.	380/255
	M	US-6,351,536	02-2002	Sasaki, Minoru	380/44

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

<b>Notice of References Cited</b>	Application/Control No. 10/046,819		Applicant(s)/Patent Under Reexamination KOBAYASHI ET AL.	
	Examiner David G. Cervetti		Art Unit 2136	Page 4 of 4

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,526,513	02-2003	Shrader et al.	726/4
	B	US-6,539,478	03-2003	Furuya et al.	713/150
	C	US-6,625,651	09-2003	Swartz et al.	709/226
	D	US-6,647,495	11-2003	Takeuchi et al.	713/189
	E	US-6,754,822	06-2004	Zhao, Jian	713/176
	F	US-6,775,536	08-2004	Geiger et al.	455/411
	G	US-6,829,708	12-2004	Peinado et al.	713/156
	H	US-2001/0016042	08-2001	Cofta et al.	380/1
	I	US-6,223,291	04-2001	Puhl et al.	726/28
	J	US-6,157,721	12-2000	Shear et al.	380/255
	K	US-5,214,702	05-1993	Fischer, Addison M.	380/30
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.